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PTO-1449 <b>Information Disclosure Citation in an Application</b>	Application No.	Applicant(s) Eoff, et al.	
	Docket Number. HES 2003-IP-009464	Group Art Unit	Filing Date

## U.S. PATENT DOCUMENTS

		DOCUMENT NO.	ISSUE/ PUB. DATE	NAME	CLASS	SUBCLASS	FILING DATE
<del>JS</del>	1	4,401,789	08/30/83	Gideon	524	827	07/14/81
<del>JS</del>	2	4,532,052	07/30/85	Weaver, et al.	252	8.55 R	08/25/82
<del>JS</del>	3	5,944,106	08/31/99	Dalrymple, et al.	166	281	08/06/97
<del>JS</del>	4	5,972,848	10/26/99	Audibert, et al.	507	119	10/15/96
<del>JS</del>	5	6,070,664	06/06/00	Dalrymple, et al.	166	281	02/12/98
<del>JS</del>	6	6,476,169	11/05/02	Eoff, et al.	523	307.2	09/28/00
<del>JS</del>	7	6,497,283	12/24/02	Eoff, et al.	166	293	11/19/01
<del>JS</del>	8	6,569,983	05/27/03	Treybig, et al.	528	102	12/20/01
<del>JS</del>	9	10/236,722	2004-03	Eoff, et al. 2004/0045712			09/06/02
<del>JS</del>	10	10/375,787	2004-09	Eoff, et al. 2004/0171495			02/27/03
<del>JS</del>	11	10/440,337	2004-11	Eoff, et al. 2004/0229756A1			05/16/03
<del>JS</del>	12	10/612,271	2005-01	Eoff, et al. 2005/0000694			07/02/03

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## FOREIGN PATENT DOCUMENTS


		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No

## NON-PATENT DOCUMENTS

		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	

EXAMINER <i>[Signature]</i>	DATE CONSIDERED 3/8/2006
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.



PTO-1449 Information Disclosure Citation in an Application	Application No. 10/763,800	Applicant(s): LARRY S. EOFF ET AL.
	Docket Number 2003-IP-009464U1	Group Art Unit 1714
		Filing Date 01/24/04

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	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
1.	5,597,783	01/28/97	Audibert, et al.	507	120	05/04/95
2.	5,637,556	06/10/97	Argillier, et al.	507	120	05/04/95
3.	5,720,347	02/24/98	Audibert, et al.	166	294	01/11/96
4.	4,814,096	03/21/89	Evani	252	8.554	08/01/83
5.	<del>US 2005/0230116</del> <del>US Pat. App. Ser. No. 11/183,028</del>	-	2007 0 0 1 2 4 4 5 Nguyen, et al.	-	-	07/15/05

### FOREIGN PATENT DOCUMENTS


	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	WO 2004/094781	11/4/04	PCT	E21 B	43/26	X	
	WO 2003/056130	07/10/03	PCT	E21B	43/26	X	
	WO 2000/78890	12/28/00	PCT	C09K	7/02	X	

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	XU, ET AL., MODELING OF LASER SPALLATION DRILLING OF ROCKS FOR GAS-AND OILWELL DRILLING, SPE 95746, 2005	
	GAHAN, ET AL., EFFECT OF DOWNHOLE PRESSURE CONDITIONS ON HIGH-POWER LASER PERFORATION, SPE 97093, 2005	
	GAHAN, ET AL., ANALYSIS OF EFFICIENT HIGH-POWER FIBER LASERS OF WELL PERFORATION, SPE 90861, 2004	
	PARKER, ET AL., WELL PERFORATION USING HIGH-POWER LASERS, SPE 84418, 2003	
	PARKER, ET AL., LASER DRILLING: EFFECTS OF BEAM APPLICATION METHODS ON IMPROVING ROCK REMOVAL, SPE 84353, 2003	
	Bai, ET AL., IMPROVED DETERMINATION OF STREE-DEPENDENT PERMEABILITY FOR ANISOTROPIC FORMATIONS, SPE 78188, 2002	
	PROETT, ET AL., ADVANCED PERMEABILITY AND ANISOTROPY MEASUREMENTS WHILE TESTING AND SAMPLING IN REAL-TIME USING A DUAL PROBE FORMATION TESTER, SPE 62919, 2000	
	PROETT, ET AL., ADVANCED DUAL PROBE FORMATION TESTER WITH TRANSIENT, HARMONIC, AND PULSED TIME-DELAY TESTING METHODS DETERMINES PERMEABILITY, SKIN AND ANISOTROPY, SPE 64650, 2000	

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PTO-1449 Information Disclosure Citation in an Application		Application No. <b>10/763,800</b>	Applicant(s) <b>Larry S. Eoff, et al</b>	
		Docket Number <b>2003-IP-009464U1</b>	Group Art Unit	Filing Date <b>01/24/2004</b>

### U.S. PATENT DOCUMENTS

	DOCUMENT NO.	ISSUE/ PUB. DATE	NAME	CLASS	SUBCLASS	FILING DATE
<del>JSF</del>	2,863,832	12/09/58	Perrine	252	8.55	05/14/54
<del>JSF</del>	2,910,436	10/27/59	Fatt, et al	252	8.55	10/02/53
<del>JSF</del>	3,215,199	11/02/65	Dilgren	166	38	02/21/63
<del>JSF</del>	3,251,415	05/17/66	Bombardieri, et al	166	42	04/01/65
<del>JSF</del>	3,297,090	<del>10/10/67</del> 1967-01	Dilgren	166	38	04/24/64
<del>JSF</del>	3,307,630	03/07/67	Dilgren, et al	166	38	06/12/64
<del>JSF</del>	3,382,924	05/14/68	Veley, et al	166	42	09/06/66
<del>JSF</del>	3,434,971	03/25/69	Atkins	252	8.55	08/25/65
<del>JSF</del>	3,441,085	04/29/69	Gidley	166	307	09/07/67
<del>JSF</del>	3,451,818 ?	06/24/69	Wareham <i>Carekvent</i>	96	78	04/19/66
<del>JSF</del>	3,910,862	10/07/75	Barabas, et al	260	79.3MU	08/27/73
<del>JSF</del>	4,129,183	12/12/78	Kalfoglou	166	300	06/30/77
<del>JSF</del>	4,158,521	06/19/79	Anderson, et al	405	264	06/26/78
<del>JSF</del>	4,299,710	11/10/81	Dupre, et al	252	8.5A	05/30/75
<del>JSF</del>	4,366,071	12/28/82	McLaughlin, et al	252	8.55R	02/04/80
<del>JSF</del>	4,366,072	12/28/82	McLaughlin, et al	252	8.55R	02/04/80
<del>JSF</del>	4,366,073	12/28/82	McLaughlin, et al	252	8.55R	02/04/80
<del>JSF</del>	4,366,074	12/28/82	McLaughlin, et al	252	8.55R	02/04/80
<del>JSF</del>	4,374,739	02/22/83	McLaughlin, et al	252	8.55R	02/04/80
<del>JSF</del>	4,393,939	07/19/83	Smith, et al	166	293	04/20/81
<del>JSF</del>	4,395,340	07/26/83	McLaughlin	252	8.55D	07/14/81
<del>JSF</del>	4,439,334	03/27/84	Borchardt	252	8.55D	07/14/81
<del>JSF</del>	4,440,649	04/03/84	Loftin, et al	252	8.5C	01/28/82
<del>JSF</del>	4,447,342	05/08/84	Borchardt, et al	252	8.55D	04/19/82
<del>JSF</del>	4,460,627	07/17/84	Weaver, et al	427	212	08/25/82
<del>JSF</del>	4,462,718	07/31/84	McLaughlin, et al	405	264	05/04/78

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EXAMINER <i>John F. Squern</i>	DATE CONSIDERED <i>3/13/2004</i>
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	Docket Number <b>2003-IP-009464U1</b>	Group Art Unit	Filing Date <b>01/24/2004</b>

### U.S. PATENT DOCUMENTS

		DOCUMENT NO.	ISSUE/PUB. DATE	NAME	CLASS	SUBCLASS	FILING DATE

### FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No
<i>JSF</i>		DE 2 250 552	04/18/74	Germany ( <i>Translation</i> )	39b4	19/00	X	
<i>JSF</i>		EP 0 383 337 A2	08/22/90	Europe	E21B	33/138	X	
<i>JSF</i>		EP 0 896 122 A2	02/10/99	Europe	E21B	33/138	X	
<i>JSF</i>		EP 1 033 378 A1 (See Equivalent, US 6,380,137 B1)	<i>2000.09</i>	<i>Derwent Abstract Only</i>				X
<i>JSF</i>		EP 1 193 365 A1	04/03/02	Europe	E21B	33/138	X	
<i>JSF</i>		EP 1 312 753 A1	05/21/03	Europe	E21B	33/138	X	
<i>JSF</i>		GB 2 221 940 A	02/21/90	UK	C09K	7/02	X	
<i>JSF</i>		WO 93/15164 (See Equivalent, US 5,972,848)	<i>Abstract Only - JSF</i> <i>1993.08</i>					X
<i>JSF</i>		WO 99/49183	09/30/99	PCT	E21B	43/02	X	
<i>JSF</i>		WO 99/50530	10/07/99	PCT	E21B	43/02	X	
<i>JSF</i>		WO 02/097236 A1	12/05/02	PCT	E21B	43/02	X	

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	Docket Number <b>2003-IP-009464U1</b>	Group Art Unit <b>1714</b>	Filing Date <b>01/24/2004</b>

### U.S. PATENT DOCUMENTS

	DOCUMENT NO.	ISSUE/PUB. DATE	NAME	CLASS	SUBCLASS	FILING DATE
<del>US</del>	US 2004/0102331 A1	05/27/04	Chan, et al	507	100	11/22/02
<del>US</del>	US 2004/0220058A1 (US Pat. App. Ser. No. 10/862,132)	11/04/04	Eoff, et al (Ref. No. 2000-IP-002244U1P1)	507	200	06/04/04
<del>US Pat. App. Ser. No. 10/763,800</del>			Eoff, et al (Ref. No. 2002-IP-009464U1)			01/24/04
<del>US Pat. App. Ser. No. 10/780,995</del>	2005.08		Eoff, et al (Ref. No. 2002-IP-007848U1)	2005/0178549		02/18/04
<del>US Pat. App. Ser. No. 10/806,894</del>	2005/0155796A1		Eoff, et al (Ref. No. 2001-IP-005267U1P2)	.	2005.07	03/23/04
<del>US Pat. App. Ser. No. 10/825,001</del>	2005/0230114 A1		Eoff, et al (Ref. No. 2002-IP-007056U2)	.	2005.10	04/15/04
<del>US Pat. App. Ser. No. 10/872,997</del>	2005.12		Eoff, et al (Ref. No. 2003-IP-011298U3)	2005/02279502		06/24/04
<del>US Pat. App. Ser. No. 10/881,198</del>	2005.12		Dalrymple, et al (Ref. No. 2003-IP-012775U1)	2005/0284632		08/29/04
<del>US Pat. App. Ser. No. 10/893,210</del>	2005.10		Eoff, et al (Ref. No. 2001-IP-005267P6)	2005/0230116		07/16/04
<del>US Pat. App. Ser. No. 11/102,062</del>	2005.09		Sierra, et al (Ref. No. 2003-IP-012775U1P1)	2005/0199396		04/08/05

*Initial Application*

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PTO-1449  Information Disclosure Citation in an Application	Application No. 10/763,800	Applicant(s) EOFF, ET AL.	
	Docket Number HES 2003-IP-009464UI	Group Art Unit 1712	Filing Date January 24, 2004

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		DOCUMENT NO.	ISSUE/ PUB. DATE	NAME	CLASS	SUBCLASS	FILING DATE
/JJF/	1	6,637,517	10/28/03	<del>Qu, et al.</del>	<del>Samuel et al.</del>		01/17/02
	2	7,008,908	03/07/06	Chan, et al.			11/22/02
	3	7,091,159	08/15/06	Eoff, et al.			09/06/02
	4	7,114,568	10/03/06	Eoff, et al.			04/15/04
	5	7,117,942	10/10/06	Dalrymple, et al.			06/29/04
	6	7,159,656	01/09/07	Eoff, et al.			02/18/04
	7	7,182,136	02/27/07	Dalrymple, et al.			07/02/03
	8	7,207,387	04/24/07	Eoff, et al.			07/16/04
	9	7,216,707	05/15/07	Eoff, et al.			06/21/04
	10	7,220,708	05/22/07	Zamora, et al.			02/27/03
/JJF/	11	2007/012445	01/18/07	Nguyen, et al.			07/15/05

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

## NON-PATENT DOCUMENTS

		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)					
/JJF/	12	Batarseh, et al., <i>Well Perforation Using High-Power Lasers</i> , "SPE 84418, 2003, Society of Petroleum Engineers Inc., presented at the SPE Annual Technical Conference and Exhibition held in Denver, Colorado, October 5-8, 2003, printed from website @ <a href="http://speonline.spe.org">http://speonline.spe.org</a> .					

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/John J. Figueroa/DATE CONSIDERED  
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